

PCN# 20190823000.1 Qualification of DMOS6 as an additional Fab site option for select devices and Datasheet Update Change Notification / Sample Request

Date: August 30, 2019 To: Newark/Farnell PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If samples or additional data are required, requests must be received within **30 days** of this notification.

The changes discussed within this PCN will not take effect any earlier than the proposed first ship date on Page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the PCN Team (<u>PCN ww admin team@list.ti.com</u>). For sample requests or sample related questions, contact your local Field Sales Representative.

PCN Team SC Business Services

20190823000.1 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE

BQ25970YFFT

CUSTOMER PART NUMBER

null

Technical details of this Product Change follow on the next page(s).

	er:	20190	90823000.1			PCN Date:		Aug 30, 2019	
I ITIQ'	itle: Qualification of DMOS6 as an additional Fab site option for select devices and Datasheet Update								
Customer Contact:			<u>CN Manager</u>		Dept	::		Quality Services	
Proposed 1 st Ship Date:		: N	ov 30, 2019	Estima Availa	nated Sample		-	Date provided at sample request.	
Change Typ	be:							- p p	
Assembly Site			Assembly Process				Assemb	ssembly Materials	
Design			Electrical Specification					lechanical Specification	
Test Site			Packing/Shipping/Labeling				Test Pro		
Wafer Bump Site X Wafer Fab Site			Wafer Bump Material Wafer Fab Materials			Wafer Bump Process Wafer Fab Process			
	ad Sile		Part number						
				Details					
Description	of Change:								
	afer Fab sour	ce for th	ne selected dev		he "Pro	odu	uct Affec		
	Current F	ab Site			Additional Fa			Site	
Current F Site	ab Proc	ess	Wafer Diameter	New Fab Site		Pr	ocess	Wafer Diameter	
RFAB	LBC	29	300mm	DMOS6		LBC9		300mm	
Device Fai	mily		Change From:			Change To:			
bq28975,	bq25971		SLUSCT3A		S	SLU	ISCT3C		
in Trave									
IEXA INST	AS TRUMENTS				SLUSCT3	c_1		bq25970, bq25971	
		ugust 201	9) to Revision C		SLUSCT3	C-1	NOVEMBER 2	bq25970, bq25971 017-REVISED AUGUST 2019 Page	
Changes fro	m Revision B (A	-		naracteristics				017-REVISED AUGUST 2019	
Changes fro Added VE	m Revision B (A 3AT Alarm Compa	arator Accu						017-REVISED AUGUST 2019 Page	
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Changes to product identification resulting from this PCN:					
Fab Site Informat	ion:				
Chip Site	Chip Site Origin Code (20L)		Chip Site Country Code (21L)	Chip Site City	
RFAB	RFB		USA	Richardson	
DMOS6	DM6		USA	Dallas	
Sample product shipping label (not actual product label) TEXAS INSTRUMENTS MADE IN: Malaysia 20: MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: Sample State DT 03/29/04 DPT: ITEM: Sample State DT 03/29/04 OPT: ITEM: Sample State DT 03/29/04 OPT: ITEM: Sample State DT 03/29/04 OPT: ITEM: Sample State DT Sample State DT					
Product Affected: BQ25970YFFR		5970YFFT			
22239,0111K	022.				

Qualification Report

Approve Date 19-July-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: BQ25970YFFR	QBS Device: BQ25910YFFR
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass
ELFR	Early Life Failure Rate, 140C	24 Hours	-	3/2400/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0
HAST	Unbiased HAST, 130C/85%RH	96 Hours	-	3/231/0
HBM	ESD - HBM	3000 V	1/3/0	3/9/0
CDM	ESD - CDM	1500 V	1/3/0	3/9/0
HTOL	Life Test, 140C	480 Hours	1/77/0	3/231/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/231/0
LU	Latch-up	(per JESD78)	1/6/0	3/18/0
TC	Temperature Cycle, -55/125C	700 Cycles	-	3/231/0

- Qual Device BQ25970YFFR is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours - The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <u>http://www.ti.com/</u>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN ww admin team@list.ti.com

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